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## 一级代理商：

深圳市弗瑞鑫电子有限公司

地址：深圳市宝安区西乡大道302号金源商务大厦B座三楼

frxelec





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5. Abol e Ma im m Ra ing (Ta=25 )

**Pa ame e**

**S mbol Ra ed Val e**

**Uni**





## 7. O de Info ma ion

Pa N mbe

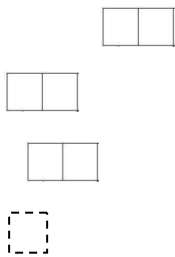
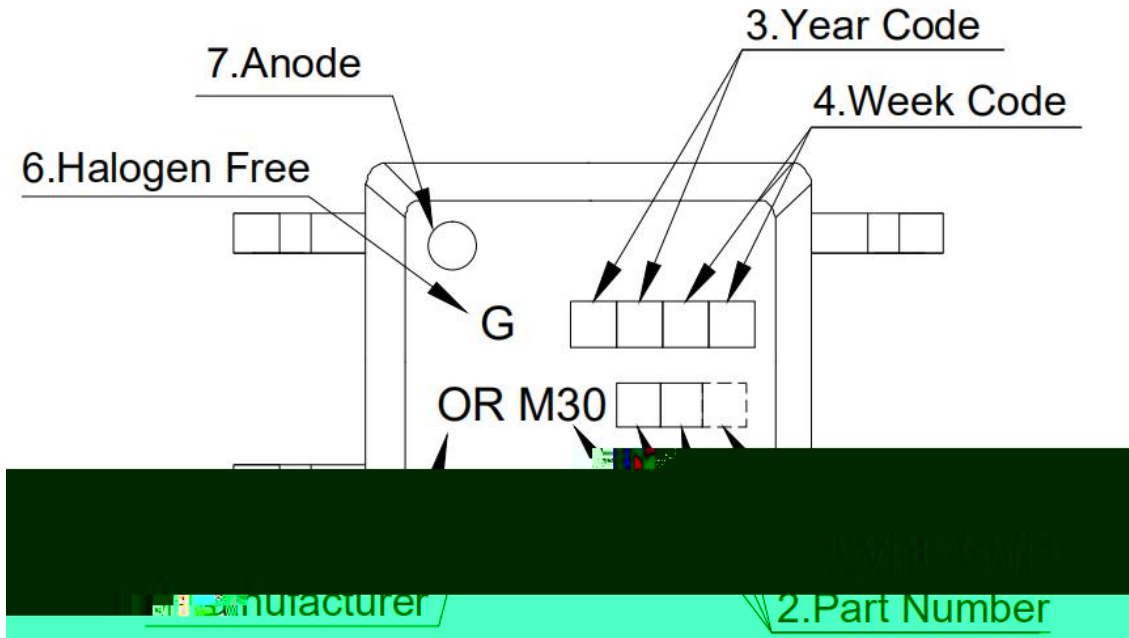
**OR-M302X-W-Y-Z**

**o OR-M305X-W-Y-Z**

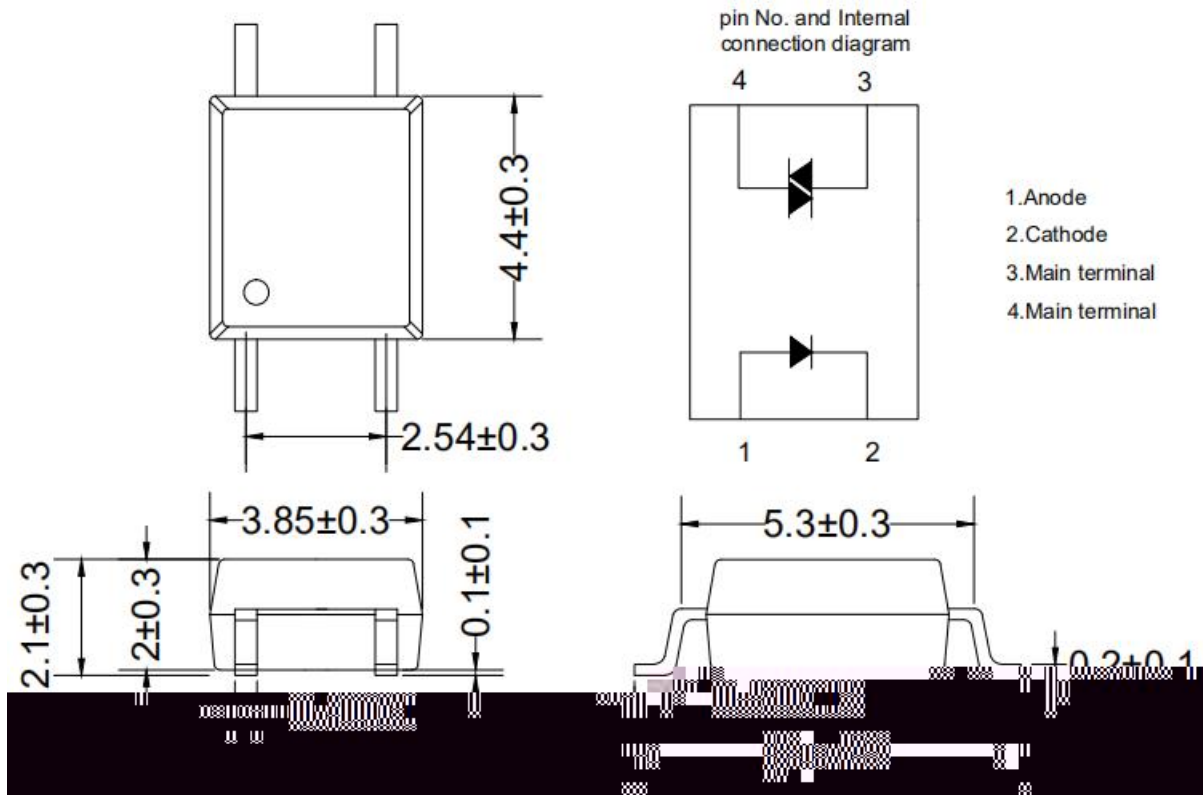
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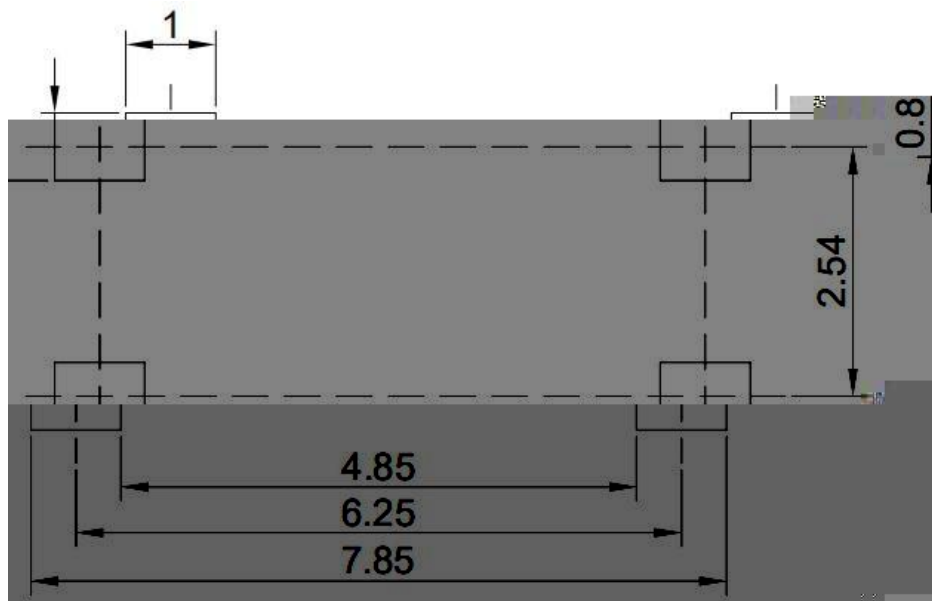
8. Naming Rule



### 9. Package Dimension

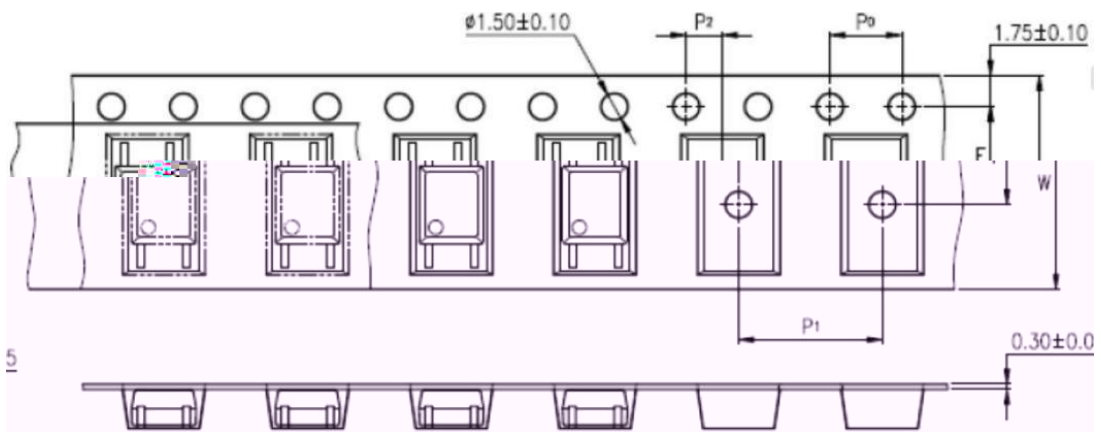
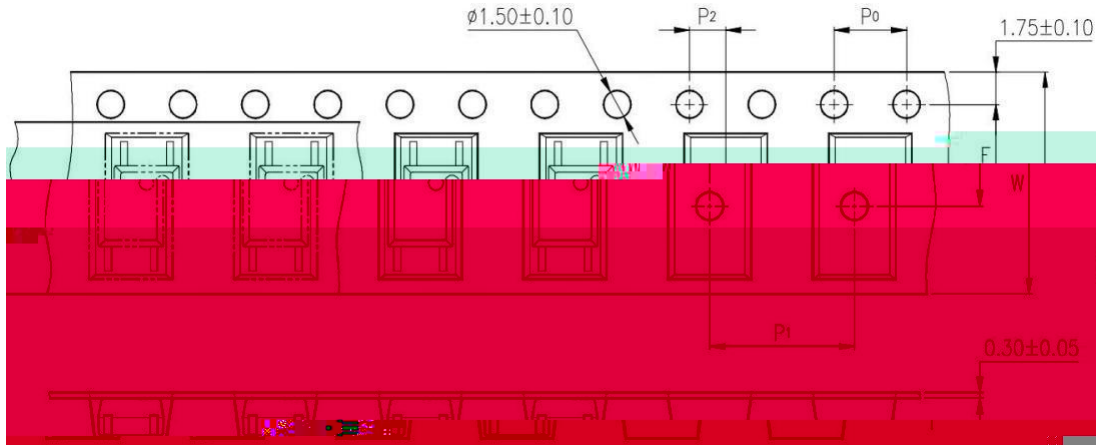


### 10. Recommended Foot Print in Package (Mo n Pad)



ni mm

### 11. Ta ing Dimen ion



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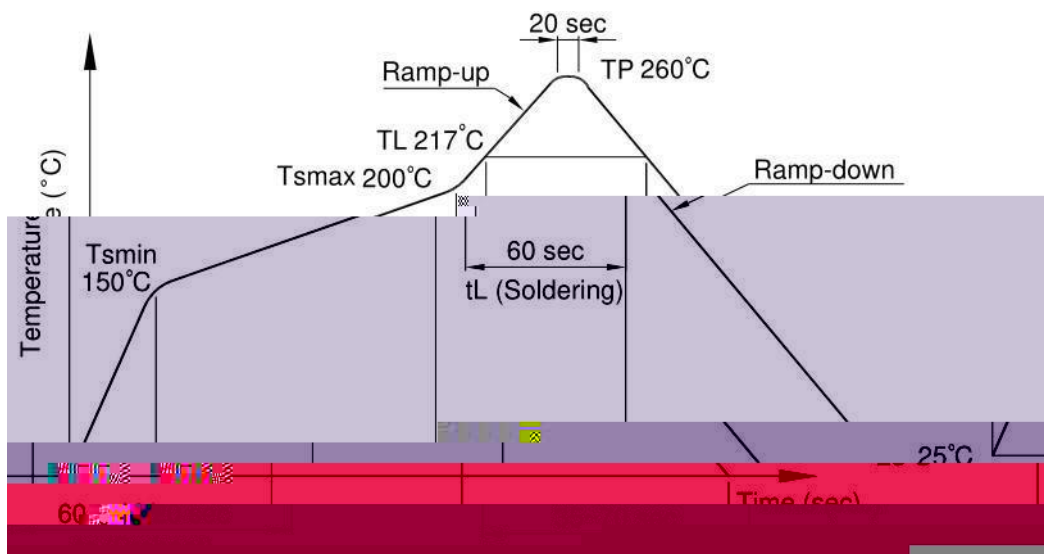
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### 13. Temperature Profile Of Soldering

| Profile Item | Condition |
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## 14. CHARACTERISTICS CURVES (TYPICAL PERFORMANCE)

Fig.1 Forward current vs Ambient temperature

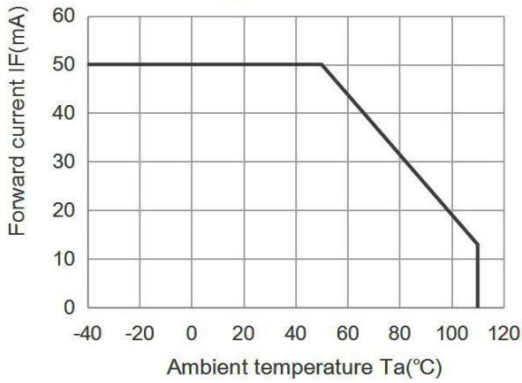


Fig.2 On-state current ITM (A) vs. Ambient temperature

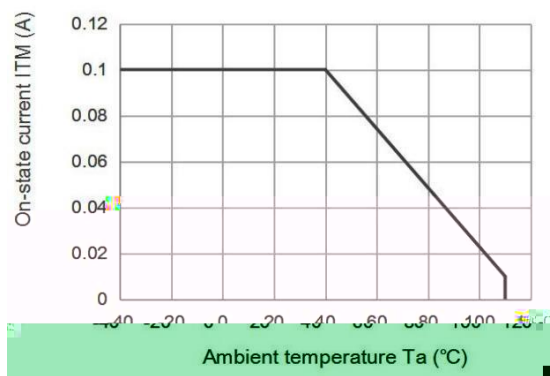


Fig.3 Minimum Trigger Current vs. Ambient temperature

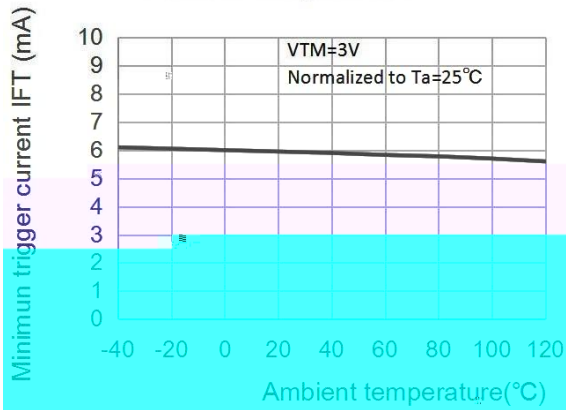


Fig.4 Forward current vs. Forward voltage

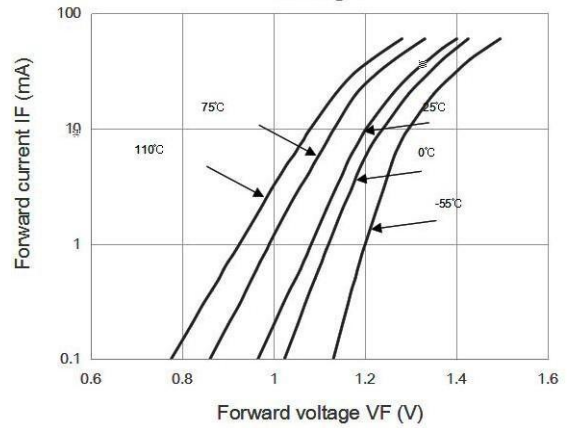


Fig.5 On-state voltage vs. Ambient temperature

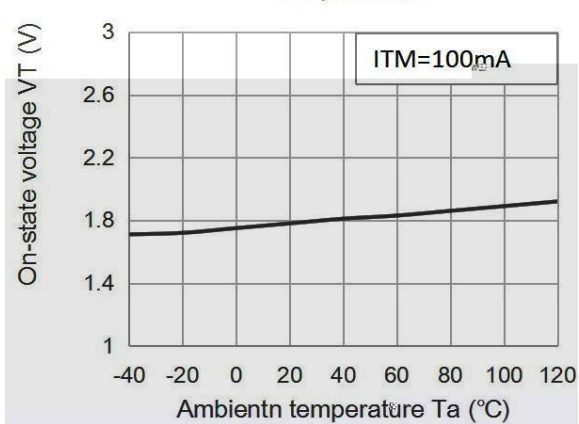


Fig.6 Holding current vs. Ambient temperature

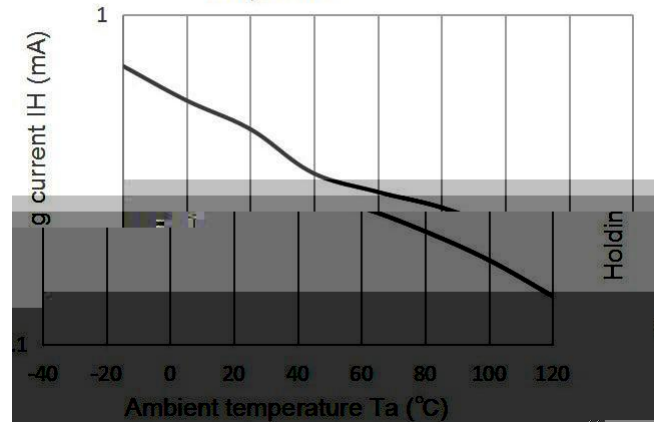


Fig.7 Repetitive peak off-state current vs. Temperature

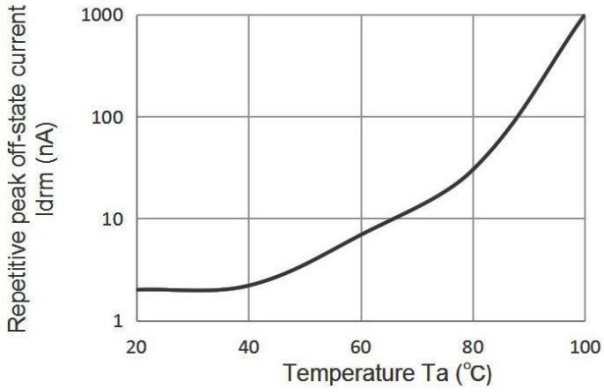
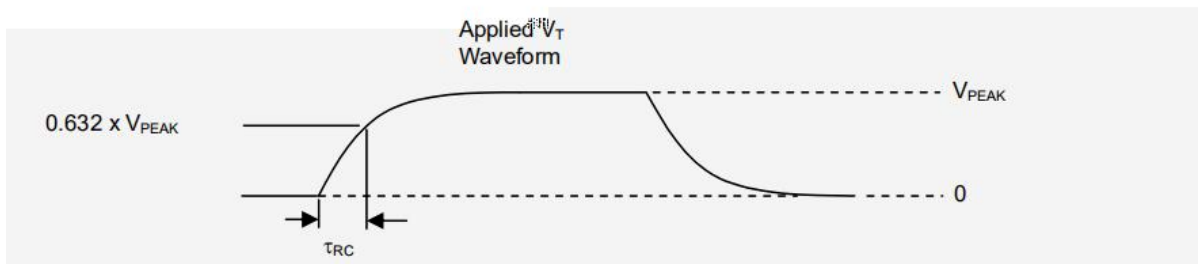
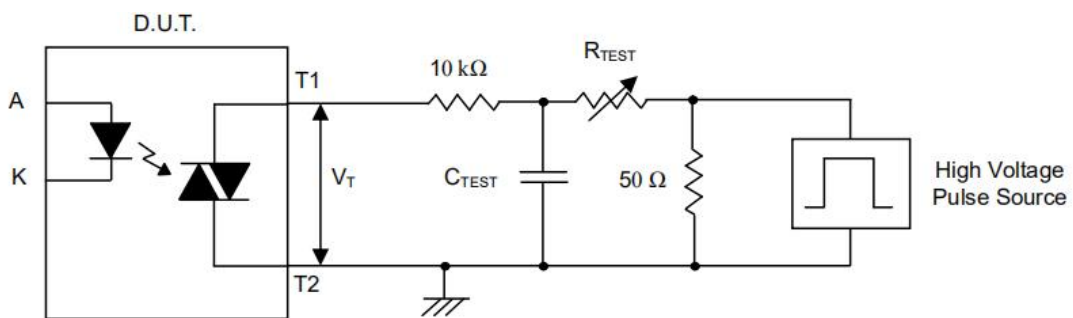
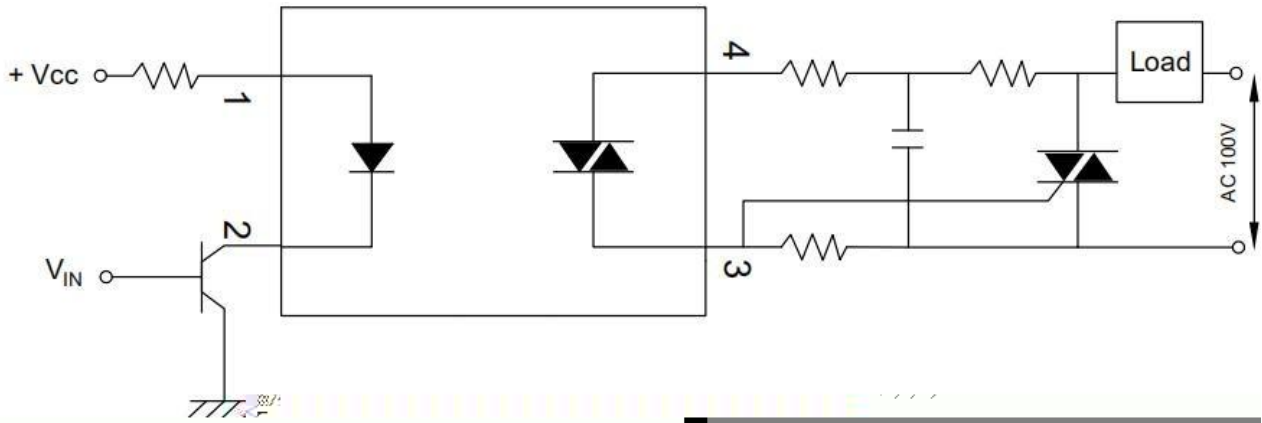
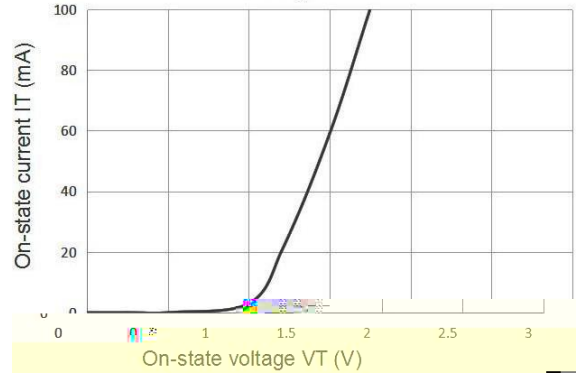


Fig.8 On-state current vs. On-state voltage



## Measurement Method

The high voltage pulse is set to the required  $V_{PEAK}$  value and applied to the D.U.T. output side through the RC circuit above. LED current is not applied. The waveform  $V_A$  is monitored using a x100 scope probe. By varying  $R_{TEST}$ , the  $dv/dt$  (slope) is increased, until the D.U.T. is observed to trigger (waveform collapses). The  $dv/dt$  is then decreased until the D.U.T. stops triggering. At this point,  $t_{TRC}$  is recorded and the  $dv/dt$  calculated.

$$\frac{dv}{dt} = \frac{0.632 \times V_{PEAK}}{t_{TRC}}$$

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For example,  $V_{PEAK} = 600V$  for EL306X-series. The  $dv/dt$  value is calculated as follows:

$$\frac{dv}{dt} = \frac{0.63 \times 600}{t_{TRC}} = \frac{378}{t_{TRC}}$$